

Specification for Approval

Date: 2014/01/14

Customer : 天河

TAI-TECH P/N: FPI0504F-101K

CUSTOMER P/N:

DESCRIPTION:

QUANTITY: _____ pcs

REMARK:		
Customer Approval Feedback		

西北臺慶科技股份有限公司
TAI-TECH Advanced Electronics Co., Ltd

西北臺慶科技股份有限公司
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SMD Type Power Inductor

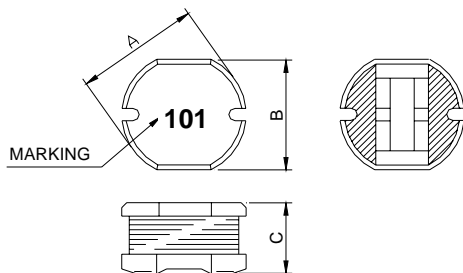
FPI0504F-101K

1. Features

- 1.Excellent solderability and high heat resistance.
- 2.Excellent terminal strength construction.
- 3.Packed in embossed carrier tape and can be used by automatic mounting machine.
- 4.100% Lead(Pb) & Halogen-Free and RoHS compliant.



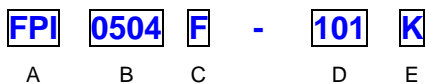
2. Dimension



Size	A(mm)	B(mm)	C(mm)
FPI 0504	5.80±0.3	5.20±0.3	4.50±0.3

Unit:mm

3. Part Numbering



A: Series

B: Dimension

C: Lead free type

D: Inductance

101=100uH

E: Inductance Tolerance

K=±10%

4. Specification

TAI-TECH Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	DCR (Ω) max.	IDC (A) max.
FPI 0504F-101K	100	±10%	1V/1K	0.70	0.60

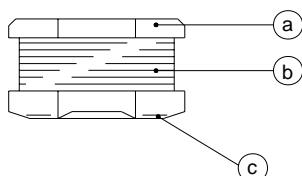
* IDC Test

For the parts with inductance under 82 uH , the L is measured at 1MHz then when a IDC current is applied, the L should drop less than 35%.

For the parts with inductance over 100 uH , the L is measured at 1KHz then when a IDC current is applied, the L should drop less than 35%.

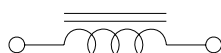
For all FPI series ,when a IDC current is applied, the temperature rised of the parts is less than 40 degree C

5. Material List



No.	Item	Material
1	Core	Ferrite DR Core
2	Wire	Enamelled Copper wire
3	Terminal	Ag+Ni+Sn

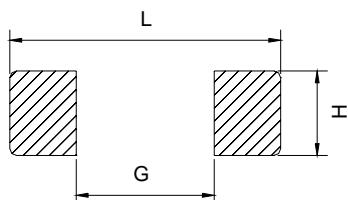
6. Schematic Diagram



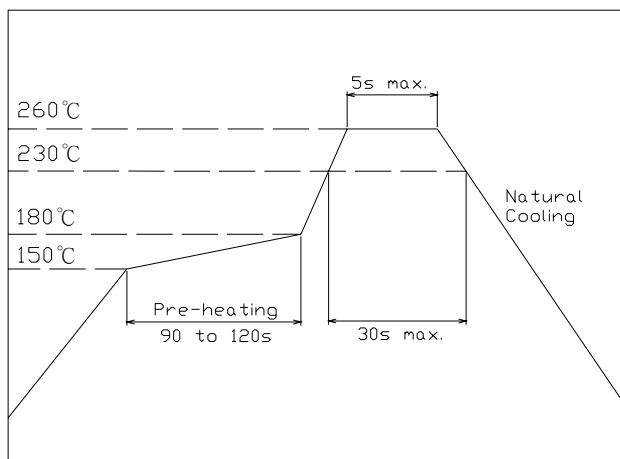
7. Reliability and Test Condition

Item	Performance	Test Condition
Operating Temperature	-25~+85°C	
Storage temperature	-25~+85°C (For products in unopened tape package, less than 40°C)	
Rated Current	Base on temp. rise & $\Delta L/LOA \leq 35\%$	
Temperature Rise Test	40°C typ. (Δt)	
Solderability	More than 90% of the terminal electrode shall be covered with fresh solder.	Preheat : 150±25°C for 60 secs Solder : Sn-Ag3.0-Cu0.5 Solder Temp.:245±5°C Flux : Rosin Dip Time : 4±1 secs
Thermal Shock Test (Temp. Cycle) MIL-STD-202G METHOD 107	Inductance shall not change more than ±10%	ROOM TEMP. → -55±2°C 5 MINUTES → 30 MINUTES ROOM TEMP. → 85±2°C 5 MINUTES → 30 MINUTES Number of cycles:100
Humidity Resistance Test MIL-STD-202G METHOD 103	Inductance shall not change more than ±10%	Temperature : 40±2°C Humidity : 90~95% Applied Current : per spec. Time : 500±8 hrs
High Temperature Resistance Test MIL-STD-202G METHOD 108	Inductance shall not change more than ±10%	Temperature : 85±2°C Applied Current : per spec. Time : 500±8 hrs
Random Vibration Test	Appearance: Cracking, shipping and any other defects harmful to the characteristics should not be allowed. Inductance: within±30%	Frequency: 10-55-10Hz for 1 min. Amplitude: 1.52mm Directions and times: X, Y, Z directions for 2 hours. A period of 2 hours in each of 3 mutually perpendicular directions (Total 6 hours).

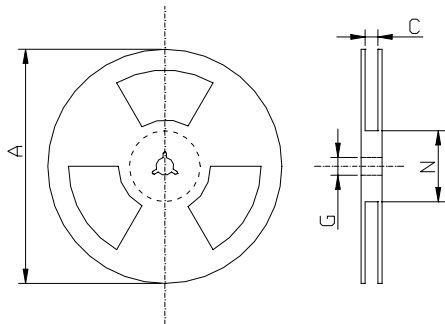
8. Recommended PC Board Pattern



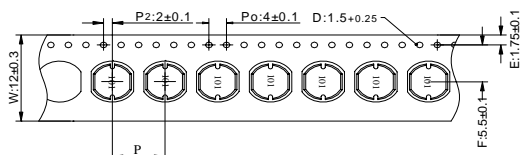
L(mm)	G(mm)	H(mm)
5.5	1.9	5.0



9. Packaging Information



Style	A(mm)	C(mm)	G(mm)	N(mm)
13"X12mm	330	14 ⁺⁰	13.5±0.5	50 ⁰

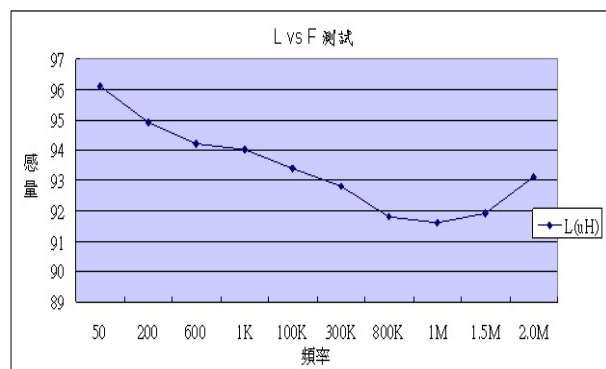
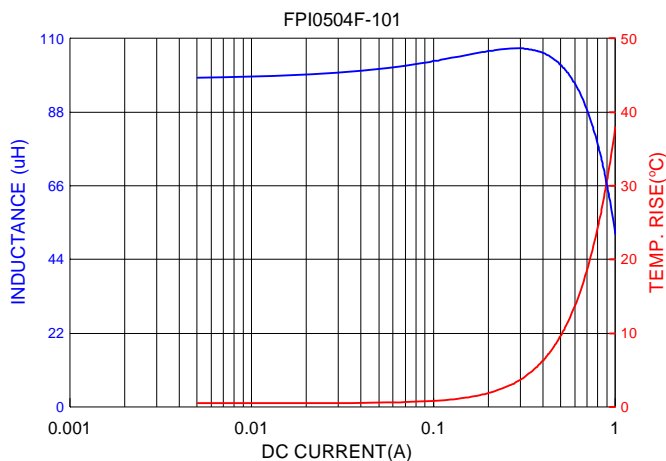


Style	W(mm)	P(mm)	D(mm)	Packaging Qty(pcs)
12 mm	12±0.3	8±0.1	1.5±0.25	1,500

Application Notice

- Storage Conditions
 - To maintain the solderability of terminal electrodes:
 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
 2. Temperature and humidity conditions: Less than 40°C and 60% RH.
 3. Recommended products should be used within 12 months form the time of delivery.
 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
 - 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
 - 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
 - 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

10. Typical Performance Curves



測試報告 Test Report

號碼(No.) : CE/2013/60553 日期(Date) : 2013/06/11 頁數(Page) : 1 of 8

西北臺慶科技股份有限公司 (TAI-TECH ADVANCED ELECTRONICS CO., LTD.)

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以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

送樣廠商(Sample Submitted By) : 西北臺慶科技股份有限公司 (TAI-TECH ADVANCED ELECTRONICS CO., LTD.)
樣品名稱(Sample Description) : WINDING POWER INDUCTOR/SMD POWER INDUCTOR
樣品型號(Style/Item No.) : LQC,LQN/FPI,FPIP,FPIG SERIES
收件日期(Sample Receiving Date) : 2013/06/04
測試期間(Testing Period) : 2013/06/04 TO 2013/06/11

=====
測試需求(Test Requested) : (1) 依據客戶指定, 進行鎘, 鉛, 汞, 六價鉻, 多溴聯苯, 多溴聯苯醚測試. (As specified by client, to test Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs contents in the submitted sample.)
(2) 依據客戶指定, 進行鹵素-氟、氯、溴、碘測試. (As specified by client, to test Halogen-Fluorine, Chlorine, Bromine, Iodine contents in the submitted sample.)
測試方法(Test Method) : 請見下一頁 (Please refer to next pages).
測試結果(Test Results) : 請見下一頁 (Please refer to next pages).


Edison
Edison Chang / Sr. Supervisor
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory - Taipei

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測試報告

Test Report

號碼(No.) : CE/2013/60553 日期(Date) : 2013/06/11 頁數(Page) : 2 of 8

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測試結果(Test Results)

測試部位(PART NAME) No.1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321: 2008方法, 以感應耦合電漿原子發射光譜儀檢測。 / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg		2	n.d.
汞 / Mercury (Hg)	mg/kg		2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321: 2008方法, 以UV-VIS檢測。 / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
鹵素 / Halogen				
鹵素(氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析。 / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)			50	n.d.
鹵素(溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)			50	n.d.
鹵素(碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)			50	n.d.

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測試報告 Test Report

號碼(No.) : CE/2013/60553 日期(Date) : 2013/06/11 頁數(Page) : 3 of 8

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result) No.1
多溴聯苯總和 / Sum of PBBs	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.
一溴聯苯 / Monobromobiphenyl			5	n.d.
二溴聯苯 / Dibromobiphenyl			5	n.d.
三溴聯苯 / Tribromobiphenyl			5	n.d.
四溴聯苯 / Tetrabromobiphenyl			5	n.d.
五溴聯苯 / Pentabromobiphenyl			5	n.d.
六溴聯苯 / Hexabromobiphenyl			5	n.d.
七溴聯苯 / Heptabromobiphenyl			5	n.d.
八溴聯苯 / Octabromobiphenyl			5	n.d.
九溴聯苯 / Nonabromobiphenyl			5	n.d.
十溴聯苯 / Decabromobiphenyl			5	n.d.
多溴聯苯醚總和 / Sum of PBDEs			-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether			5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether			5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether			5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether			5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether			5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	5	n.d.		
十溴聯苯醚 / Decabromodiphenyl ether	5	n.d.		

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測試報告 Test Report

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備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. 樣品的測試是基於申請人要求混合測試，報告中的混合測試結果不代表其中個別單一材質的含量。
(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing.
The above results was/were only given as the informality value.)

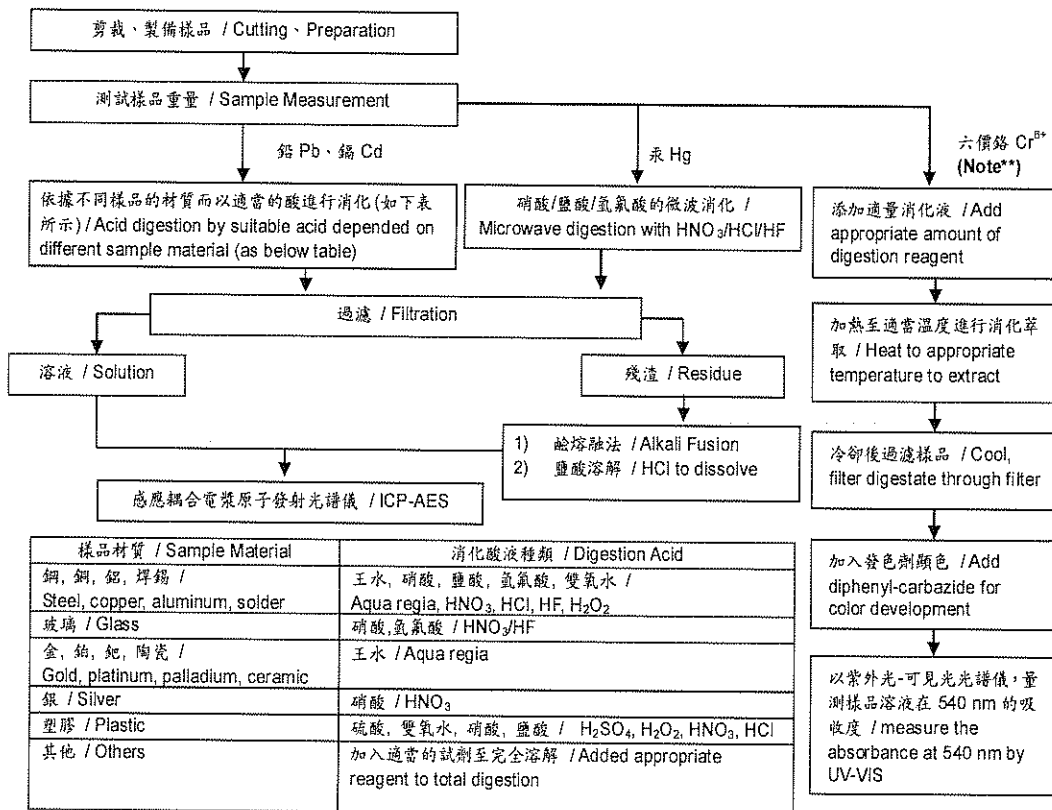
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測試報告 Test Report

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- 1) 根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 測試人員：楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



Note**:(1) 針對非金屬材料加入鹼性消化液, 加熱至 90~95°C 萃取. / For non-metallic material, add alkaline digestion reagent and heat to 90~95°C.
 (2) 針對金屬材料加入純水, 加熱至沸騰萃取. / For metallic material, add pure water and heat to boiling.

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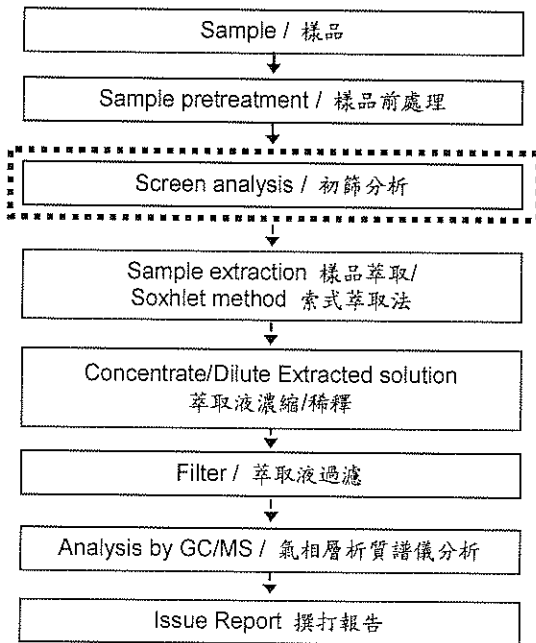
號碼(No.) : CE/2013/60553 日期(Date) : 2013/06/11 頁數(Page) : 6 of 8

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多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang
- 初次測試程序 / First testing process ———▶
- 選擇性篩檢程序 / Optional screen process▶
- 確認程序 / Confirmation process - - - ▶



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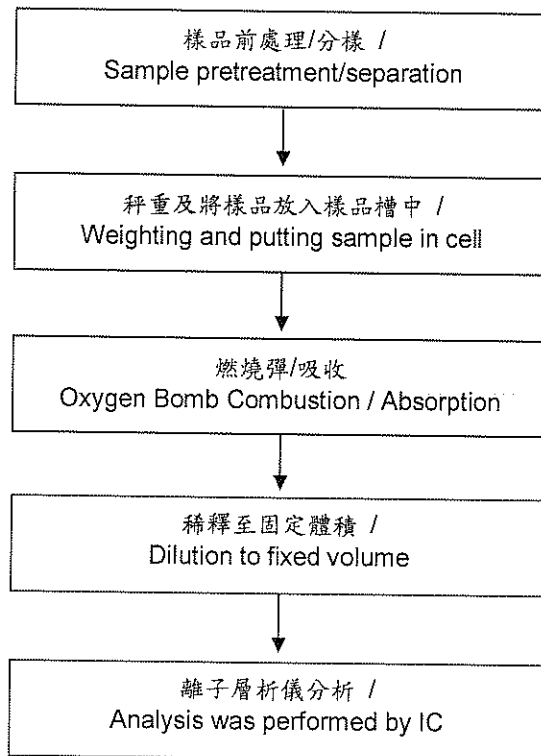
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鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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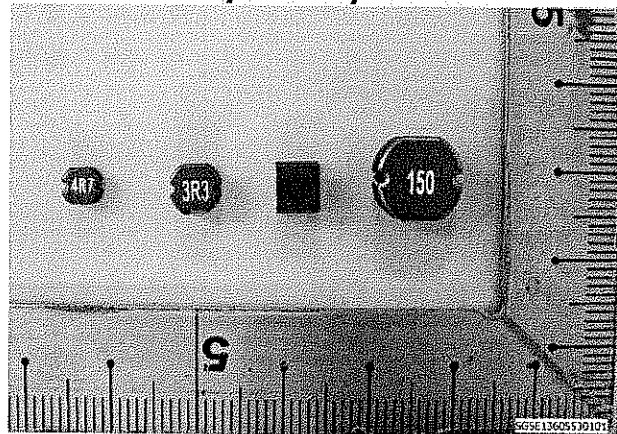
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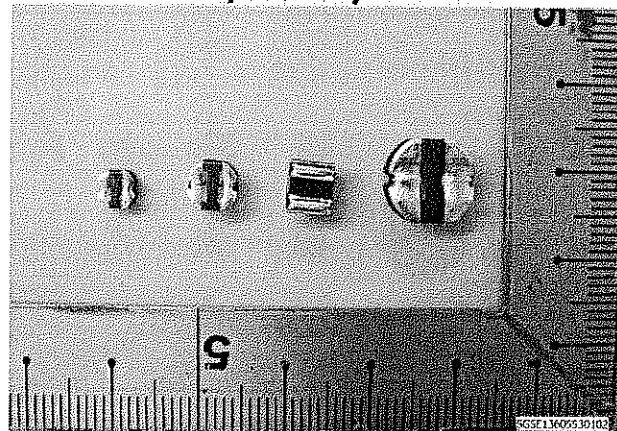
* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

CE/2013/60553



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** 報告結尾(End of Report) **

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